



Title of Change:	Update Notice of FPCN20832 - Reliability Data update of NTMFS4C05NT1G.				
Proposed first ship date:	31 December 2015				
Contact information:	Contact your local ON Semiconductor Sales Office or <MohdHezri.AbuBakar@onsemi.com>				
Samples:	Contact your local ON Semiconductor Sales Office or <Michael.Mooney@onsemi.com>				
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Don.Knudsen@onsemi.com>				
Type of notification:	ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.				
Change category:	<input checked="" type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input type="checkbox"/> Other _____				
Change Sub-Category(s):	<input checked="" type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Manufacturing Process Change		<input type="checkbox"/> Material Change <input type="checkbox"/> Product specific change		<input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Other: _____
Sites Affected:	<input type="checkbox"/> All site(s) <input type="checkbox"/> not applicable		<input checked="" type="checkbox"/> ON Semiconductor site(s) : ON Pocatello, Idaho		<input type="checkbox"/> External Foundry/Subcon site(s)
Description and Purpose:					
This Update Notification is issued to customers to provide updated Reliability data of HTRB and HTGB at 1008 hrs from the qualification vehicle of NTMFS4C05NT1G.					
FPCN20832 was issued to customers to inform ON Semiconductor's plan to qualify and add capacity in FAB10 for the 30V Trench (T6) MOSFET technology. FAB10 is an internal wafer fab within ON Semiconductor located in Pocatello, ID. At the expiration of this notification, all products listed here will be dual sourced from its current ON Semiconductor wafer fab in Gresham and FAB10.					
Reliability Data Summary:					
QV Name: NTMFS4C05NT1G Package: SO8FL					
Test	Specification	Condition	Interval	Sample Size	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated Vdss	1008 hrs	84 pcs/3 lots	0/252
HTGB	JESD22-A108	Ta=150°C, 100% max rated Vgss	1008 hrs	84 pcs/3 lots	0/252
HTSL	JESD22-A103	Ta=150°C	2016 hrs	84 pcs/3 lots	0/252
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15000 cyc	84 pcs/3 lots	0/252
TC	JESD22-A104	Ta=-55°C to +150°C	2000 cyc	84 pcs/3 lots	0/252
HAST	JESD22-A110	131°C, 85% RH, 18.8psig, bias	96 hrs	84 pcs/3 lots	0/252
uHAST	JESD22-A118	131°C, 85% RH, 18.8psig, unbiased	96 hrs	84 pcs/3 lots	0/252
Electrical Characteristic Summary:					
There is no change in electrical parametric performance. Characterization data is available upon request.					

**List of Affected Standard Parts:**

Part Number	Qualification Vehicle
NTMFS4C05NT1G	NTMFS4C05NT1G
NTMFS4C05NT3G	NTMFS4C05NT1G
NTMFS4C06NT1G	NTMFS4C05NT1G
NTMFS4C08NT1G	NTMFS4C05NT1G
NTMFS4C08NT3G	NTMFS4C05NT1G
NTMFS4C09NT1G	NTMFS4C05NT1G
NTMFS4C09NT3G	NTMFS4C05NT1G
NTMFS4C10NT1G	NTMFS4C05NT1G
NTMFS4C13NT1G	NTMFS4C05NT1G
NTMFS4C13NT3G	NTMFS4C05NT1G
NTMFS4C50NT1G	NTMFS4C05NT1G
NTMFS4C50NT3G	NTMFS4C05NT1G
NTMFS4C53NT1G	NTMFS4C05NT1G
NTMFS4C53NT3G	NTMFS4C05NT1G
NTMFS4C55NT1G	NTMFS4C05NT1G
NTMFS4C55NT3G	NTMFS4C05NT1G
NTMFS4C56NT1G	NTMFS4C05NT1G
NTMFS4C56NT3G	NTMFS4C05NT1G
NTMFS4C58NT1G	NTMFS4C05NT1G
NTMFS4C58NT3G	NTMFS4C05NT1G
NTMFS4C59NT1G	NTMFS4C05NT1G
NTMFS4C59NT3G	NTMFS4C05NT1G